OPEN ACCESS

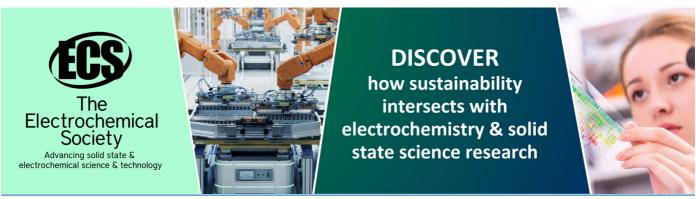
Crystallization paths in ${\rm SiO_2}$ - ${\rm Al_2O_3}$ -CaO system as a genotype of silicate materials

To cite this article: V I Lutsyk and A E Zelenaya 2013 IOP Conf. Ser.: Mater. Sci. Eng. 47 012047

View the article online for updates and enhancements.

You may also like

- <u>Laboratory Soft X-ray XAFS: The Local Structure of K₂O-SiO₂ Glasses</u> Nagao Kamijo and Norimasa Umesaki
- <u>Luminescent Properties of a Novel Mn²⁺ doped 3CaO-CaF₂₋₂SiO₂ Glasses
 Ning Zhang and Shiqing Man</u>
- Structure change of soda-silicate glass by mechanical milling
 M Iwao and M Okuno



doi:10.1088/1757-899X/47/1/012047

Crystallization paths in SiO₂-Al₂O₃-CaO system as a genotype of silicate materials

V I Lutsyk¹ and A E Zelenaya¹

¹Institute of Physical Materials Science (Siberian Branch of Russian Academy of Sciences), Ulan-Ude, Russian Federation

E-mail: vluts@ipms.bscnet.ru

Abstract. The phases trajectories in the fields of primary crystallization of cristobalite (SiO₂^{cr}), tridymite (SiO₂^{tr}), mullite (3Al₂O₃·2SiO₂) and in a field of liquid immiscibility are analyzed on a basis of computer model for T-x-y diagram of SiO₂-Al₂O₃-CaO system. The concentration fields with unique set of microconstituents and the fields without individual crystallization schemes and microconstituents are revealed.

1. Introduction

A phase diagram of system SiO₂-Al₂O₃-CaO (S-A-C) has wide applications and can be used in the cement industry to describe the properties of Portland and aluminous cements [1-3], and in studies of refractories and alkali-free glass [4]. To extend the capabilities of research and examine the processes of crystallization for S-A-C system allows its computer model [5-6]. Analysis of concentration fields obtained by the projection of phase regions onto Gibbs triangle allows to establish the boundaries of phase regions (located above the considered fields), the sequence of phase transformations and microstructural elements in crystallized initial melt at the equilibrium condition. Based on this technology, the research identifies fields with coinciding sets of crystallization scheme and microconstituents and the fields with individual characteristics.

2. T-x-v diagram model for SiO₂-Al₂O₃-CaO (S-A-C) system

The experimental data about the structure of S-A-C presented in the literature is usually confined to the surface of the primary crystallization (figure 1a) and triangles of coexistent phases [1-2, 7-9]. The spatial scheme of mono and invariant equilibria permits to restore the full construction of phase diagram. In the first stage a position of invariant planes are reproduced (figure 1b). Then the ruled surfaces of three-phase region borders are formed.

Let's consider the fragment of scheme adjoining to the component SiO_2 (figure 1c). The plane of four-phase regrouping of phases $L_U + SiO_2^{cr} \rightrightarrows R_5 + SiO_2^{tr}$ has a degenerated structure $U - R5_U - S1_U (S2_U)$ ($S1 = SiO_2^{cr}$ and $S2 = SiO_2^{tr}$, cr – cristobalite, tr - tridymite), because the points $S1_U$ and $S2_U$ coincide together. Two ruled surfaces $S1_{e4} - e_4 - U - S1_U$ and $R5_{e4} - e_4 - U - R5_U$ bounding the phase region L + S1 + R5 fit to the plane. The plane of ternary eutectic point E_4 : $L^{E4} \rightarrow S2^{E4} + R5^{E4} + R12_2^{E4}$ ($S2_{E5} - R5_{E5} - R12_{E5}$) is arranged below. Three pairs of ruled surfaces ($S2_U - U - E_5 - S2_{E5}$, $R5_U - U - E_5 - R5_{E5}$; $S2_{E4} - E_4 - [E_4, E_5] - S2_{E4, E5}$, $R12_{E4} - E_4 - [E_4, E_5] - R12_{[E4, E5]}$; $R5_{Q8} - Q_8 - E_5 - R5_{E5}$, $R12_{Q8} - Q_8 - E_5 - R12_{E5}$) are bounded the phase regions L + S2 + R5, L + S2 + R12, L + R5 + R12. The ruled surfaces $S2_{E4} - E_4 - [E_4, E_5] - S2_{E4, E5}$, $R12_{E4} - E_4 - [E_4, E_5] - R12_{E4, E5}$ are formed from the maximum point $[E_4, E_5]$ on monovariant curve E_4E_5 . Three-phase region S2 + R5 + R12 situates below the simplex $S2_{E5} - R5_{E5} - R12_{E5}$.

Content from this work may be used under the terms of the Creative Commons Attribution 3.0 licence. Any further distribution of this work must maintain attribution to the author(s) and the title of the work, journal citation and DOI.

Step-by-step restoring of phase regions boundaries permits to obtain the complete model of phase diagram (figure 1d).

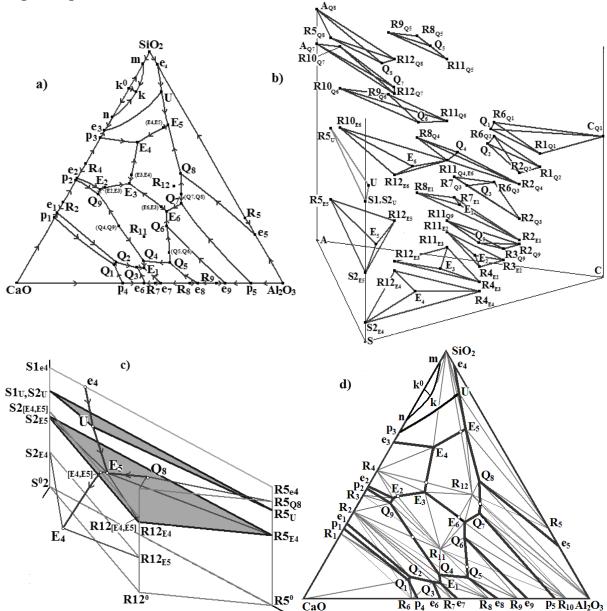


Figure 1. XY projection of primary crystallization surfaces (a); 3D scheme of invariant planes arrangement (b) and three-phase regions of diagram fragment adjoining to the component S (c); XY projection of all phase regions (d) $(R_1=C_3S, R_2=C_2S, R_3=C_3S_2, R_4=CS, R_5=A_3S_2, R_6=C_3A, R_7=C_{12}A_7, R_8=CA, R_9=CA_2, R_{10}=CA_6, R_{11}=C_2AS, R_{12}=CAS_2)$.

The projection of phase regions of system S-A-C divides the Gibbs triangle onto 117 two-dimensional, 163 one-dimensional and 45 zero-dimensional concentration fields. It is previously found that the projection of primary crystallization fields CaO, C₃S and C₃A are divided onto 52 concentration fields (19 two-, 21 one- and 12 zero-dimensional), among which 18 fields (12 one- and 6 zero-dimensional) haven't unique set of microconstituents [10].

doi:10.1088/1757-899X/47/1/012047

Let's consider the fragment of phase diagram adjoining to component SiO_2 and carry out the analysis of concentration fields under the surfaces of primary crystallization cristobalite (SiO_2^{cr}), tridymite (SiO_2^{tr}), mullite (A_3S_2) and a cupola of melt immiscibility (i).

3. Structure of phase diagram adjacent to component SiO₂

There are 18 ruled surfaces, 4 horizontal planes at the temperatures of invariant points (E_4 , E_5 , Q_8 , U), 4 vertical triangulation planes under the fields of primary crystallization SiO_2^{cr} (surface Q_{S1} with the contour mknp₃Ue₄S), SiO_2^{tr} ($Q_{S2}-e_3E_4[E4,E5]E_5Up_3$), A_3S_2 ($Q_{A3S2}-e_4UE_5Q_8e_5R5$) and the surface of immiscibility melt ($i-k^0$ nkm) (figure 2, table 1). The following designations are used: e and p – binary eutectic and peritectic points, m and n – binary points of monotectic segment, E and Q – ternary eutectic and quasiperitectic points, U – point of the four-phase regrouping with participation of two polymorphous modifications SiO_2^{cr} and SiO_2^{tr} , $[E_4,E_5]$ – maximum point on the monovariant curve E_4E_5 .

16 phase regions are located under the considered fields of primary crystallization: L_1+L_2 , L+S1, L+S2, $L+A_3S_2$, $S+CAS_2$, $A+CAS_2$, $CS+CAS_2$, $A_3S_2+CAS_2$, L_1+L_2+S1 , L+S1+S2, L+S2+CS, $L+S2+CAS_2$, $L+A_3S_2+CAS_2$, L+

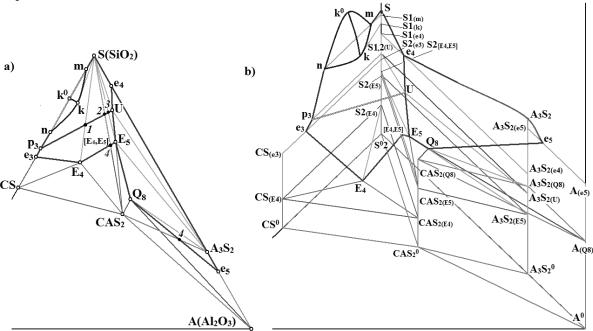


Figure 2. XY projection (a) and 3D model (b) of fragment of system S-A-C phase diagram.

Table 1. Contours of ruled surfaces (Q^r, i^r), horizontal (H) and vertical (V) planes.

Symbol	Contour	Symbol	Contour
Q ^r _{e4_ A3S2}	$A_3S_{2(e4)}$ - e_4 - U - $A_3S_{2(U)}$	Q ^r _{E4E5_R12}	$CAS_{2(E4)}$ - E_4 - $[E_4,E_5]$ - $CAS_{2[E4,E5]}$
$Q^{r}_{E5U_A3S2}$	$A_3S_{2(U)}$ -U-E ₅ - $A_3S_{2(E5)}$	$Q^{r}_{E5E4_R12}$	$CAS_{2(E5)}$ - E_5 - $[E_4,E_5]$ - $CAS_{2[E4,E5]}$
$Q^{r}_{Q8E5_A3S2}$	$A_3S_{2(Q8)}$ - Q_8 - E_5 - $A_3S_{2(E5)}$	\mathbf{i}^{r}	m-k-n
$Q^{r}_{e5_A3S2}$	$A_3S_{2(e5)}$ - e_5 - Q_8 - $A_3S_{2(Q8)}$	i^r_{m}	$S1_{(mn)}$ -m-k- $S1_{(k)}$
$Q^{r}_{\ e4_S}$	$S1_{(e4)}$ - e_4 - U - $S1_{(U)}$	i ^r n	$S1_{(mn)}$ -n-k- $S1_{(k)}$
$Q^{r}_{E5U_S}$	$S2_{(U)}$ -U-E ₅ - $S2_{(E5)}$	${ m H}_{ m E4}$	$S2_{(E4)}$ - CS_{E4} - $CAS_{2(E4)}$
$Q^{r}_{e5_A}$	$A_{(e5)}$ - e_5 - Q_8 - $A_{(Q8)}$	H_{E5}	$S2_{E5}$ - $A_3S_{2(E5)}$ - $CAS_{2(E5)}$
$Q^{r}_{Q8E5_CAS2}$	$CAS_{2(Q8)}$ - Q_8 - E_5 - $CAS_{2(E5)}$	${ m H}_{ m Q8}$	Q_8 - $A_3S_{2(Q8)}$ - A - $CAS_{2(Q8)}$

IOP Conf. Series: Materials Science and Engineering 47 (2013) 012047

doi:10.1088/1757-899X/47/1/012047

$Q^{r}_{e3_S}$	$S2_{(e3)}$ - e_3 - E_4 - $S2_{(E4)}$	H_{U}	$U-A_3S_{2(U)}-S1_{(U)},S_{2(U)}$
$Q^{r}_{p3_S}$	$S1_{(U)}$ - p_3 - U	V_{S-CAS2}	$S2_{[E4,E5]}$ - $CAS_{2[E4,E5]}$ - CAS_{2}^{0} - $S2^{0}$
$Q^{r}_{E4E5_S}$	$S2_{(E4)}$ - E_4 - $[E_4,E_5]$ - $S2_{[E4,E5]}$	V_{A-CAS2}	A_{Q8} - $CAS_{2(Q8)}$ - CAS_2^0 - $A_3S_2^0$
$Q^{r}_{E5E4_S}$	$S2_{(E5)}$ - E_5 - $[E_4,E_5]$ - $S2_{[E4,E5]}$	$V_{R5\text{-}CAS2}$	$A_3S_{2(Q8)}$ - $CAS_{2(Q8)}$ - CAS_2^0 - $A_3S_2^0$
$Q_{e3_CS}^{r}$	E_3 - E_4 - CS_{E4} - CS_{e3}	$V_{R4\text{-}CAS2}$	$CS_{(E4)}$ - $CAS_{2(E4)}$ - CAS_2^0 - CS^0

Table 2. Phase regions structure.

Symbol	Bounding surfaces	Symbol	Bounding surfaces
L_1+L_2	i, i ^r	$L+A_3S_2+CAS_2$	Q ^r _{Q8E5_A3S2} , Q ^r _{Q8E5_CAS2} , H _{Q8} , H _{E5} ,
			$V_{A3S2\text{-}CAS2}$
L+S1	$Q_{S1}, i^r, Q^r_{e4_S}, Q^r_{p3_S}$	S2+CS+CAS ₂	$V_{S-CAS2}, V_{CS-CAS2}, H_{E4}$
L+S2	$Q_{S2}, Q_{e3_S}^r, Q_{p3_S}^r, Q_{E5U_S}^r,$	$A_3S_2+CAS_2+A$	H_{Q8} , $V_{A\text{-CAS2}}$, $V_{A3S2\text{-CAS2}}$
	$Q^{r}_{E4E5_S}, Q^{r}_{E5E4_S}$		
$L+A_3S_2$	$Q_{A3S2}, Q_{e4_A3S2}^r, Q_{E5U_A3S2}^r$	$S2+A_3S_2+CAS_2$	$V_{A3S2-CAS2}, V_{S-CAS2}, H_{E5}$
	$Q^{r}_{Q8E5_A3S2}, Q^{r}_{e5_A3S2}$		
$L_1 + L_2 + S1$	i ^r , i ^r _n , i ^r _m	S2+CAS ₂	V_{S-CAS2}
L+S1+S2	Q^{r}_{p3}	$A+CAS_2$	V_{A-CAS2}
L+S2+CS	$Q_{e3_CS}^{r}, Q_{e3_S}^{r}, H_{E4}$	$A_3S_2+CAS_2$	$V_{A3S2\text{-}CAS2}$
L+S2+CAS ₂	$Q^{r}_{E4E5_S}, Q^{r}_{E5E4_S}, Q^{r}_{E5E4_CAS2},$	CS+CAS ₂	$V_{CS\text{-}CAS2}$
	$Q^{r}_{E4E5_CAS2}, H_{E4}, H_{E5}, V_{S-CAS2}$		

4. Analysis of the concentration fields

At projection the surfaces Q_{S1} , Q_{S2} , Q_{A3S2} and i are divided onto 15 two-, 28 one- and 9 zero-dimensional concentration fields. Thirteen (2 two-, 8 one-and 3 zero-dimensional) fields coincide with neighbouring fields by the set of microconstituents.

The microconstituents of concentration fields corresponding to the regions of immiscibility melt (m-n-k, SiO₂-m-k, SiO₂-k, n-k, m-k, k) coincide with the of field p_3 -1-SiO₂-k-n. Meanwhile the fields m-n-k, SiO₂-m-k and m-k duffer from field p_3 -1-SiO₂-k-n by intersected surfaces, phase regions and crystallization scheme (table 3). The phase region L+S₁ and phase region of immiscibility melt L+S₁+S₂ are located under the field SiO₂-m-k. At that the phase region L+S₁ is twice crossed for this field. So the field is characterized by two primary crystallization reactions L¹ \rightarrow S₁¹ between which the monotectic reaction L₁^m \rightarrow L₂^m+S₁^m takes place. Field m-n-k arranges under the surface of immiscibility melt (i) and intersects the phase regions L₁+L₂ μ L₁+L₂+S₁, where the phase reaction L₁¹ \rightarrow L₂¹ μ L₁^m \rightarrow L₂^m+S₁^m occur.

Since the process of melt immiscibility ends in the phase region $L_1+L_2+B_1$, then the reaction products L_2^{-1} and L_2^{-m} doesn't influence on the microconstituents forming. The crystals B_1 are not present in the microconstituents, because they are fully disappeared in the reactions $L^p, B_1 \rightarrow B_2^p$ and $L^U, S_1 \rightarrow S_2^U + A_3S_2^U$ and in the subsequent phase transformations there are only B_2 crystals. The reactions $L^p, S_1 \rightarrow S_2^p$ and $L^U, S_1 \rightarrow S_2^U + A_3S_2^U$ have degenerated form as the result of degeneration of phase regions $L+S_1+S_2$ in horizontal line and four-phase plane in the triangle $U-A_3S_{2(U)}-S1_{(U)},S_{2(U)}$ [11].

The fields SiO_2 -k, n-k and k coincide with field p_3 -1- SiO_2 -k-n by the list of phase reactions and the microconstituents.

Table 3. Crystallization scheme and microconstituents for surface of immiscibility i and the fragment of primary crystallization surface Q_{S1} of high-temperature modification $SiO_{2}^{cr}(S1)$ *.

Concentration	Intersected	Intersected	Crystallization scheme	Microconstituents
fields	surfaces	phase regions		
p ₃ -1-SiO ₂ -k-n	Q_{S1} ,	$L+S_1$,	$L^1 \rightarrow S_1^1$,	
	Q^{r}_{p3-S}	$L+S_1+S_2$,	$L^p + S_1^1 \rightarrow S_2^p$	S_2^p ,
	Q_{e3-S}^{r}	$L+S_2$,	$L^{1p} \rightarrow S_2^{1p}$,	S_2^{1p} ,

	H_{E4}	L+S ₂ +CS	$L^{ep} \rightarrow S_2^{ep(CS)} + CS_4^{ep(B2)}$	$S_2^{ep(CS)}$, $CS^{ep(B2)}$
	11 <u>E</u> 4	B ₂ +CS+CAS ₂	$L \xrightarrow{\mathcal{S}_2} CS_4$ $L^{E4} \rightarrow S_2^{E4} + CS_4^{E4} + CAS_2^{E4}$	
SiO ₂ -m-k	Q_{S1} ,	$L+S_1$,	$L^1 \rightarrow S_1^1$,	_ , , ,
2	i ^r m,	$L_1+L_2+S_1$,	$L_1^m \rightarrow L_2^m + S_1^m$	
	i ^r n,	$L+S_1$,	$L^1 \rightarrow S_1^1$	
	Q^{r}_{p3-S} ,	$L+S_1+S_2$,	$L^p + S_1^{1,1p} \rightarrow S_2^p$	S_2^p ,
	Q_{e3-S}^{r}	$L+S_2$,	$L^{1p} \rightarrow S_2^{1p}$	S_2^{1p} , $S_2^{ep(CS)}$, $CS^{ep(B2)}$
	$ m H_{E4}$	$L+S_2+CS$,	$L^{ep} \rightarrow S_2^{ep(CS)} + CS^{ep(B2)}$	$S_2^{\text{ep(CS)}}$, $CS^{\text{ep(BZ)}}$
		$S_2+R_4+CAS_2$	$L^{E4} \rightarrow S_2^{E4} + CS^{E4} + CAS_2^{E4}$	S_2^{E4} , CS^{E4} , CAS_2^{E4}
m-n-k	i,	L_1+L_2 ,	$L_1^1 \rightarrow L_2^1$,	
	i ^r ,	$L_1+L_2+S_1$,	$L_1^m \rightarrow L_2^m + S_1^m$,	
	i'n,	$L+S_1$,	$L^1 \rightarrow S_1^1$,	a n
	Q_{p3-S}^{r}	$L+S_1+S_2$,	$L^p + S_1^1 \longrightarrow S_2^p$,	S_2^p ,
	$Q^{\mathrm{r}}_{\mathrm{e}3 ext{-S}}, \ H_{\mathrm{E}4}$	L+S ₂ , L+S ₂ +CS,	$L^{1p} \rightarrow S_2^{1p}$,	S_2^{1p} , $S_2^{ep(CS)}$, $CS^{ep(B2)}$
	11 <u>E</u> 4	$S_2+CS+CAS_2$	$L^{ep} \rightarrow S_2^{ep(CS)} + CS^{ep(B2)}$ $L^{E4} \rightarrow S_2^{E4} + CS^{E4} + CAS_2^{E4}$	S_2^{E4} , CS^{E4} , CAS_2^{E4}
G:O 1		L + C	$L^{E4} \rightarrow S_2^{E4} + CS^{E4} + CAS_2^{E4}$	S_2 , S_3 , S_4
SiO ₂ -k	Q_{S1} ,	$L+S_1$,	$L^1 \rightarrow S_1^1$,	C p
	$Q^{r}_{p3-S}, Q^{r}_{e3-S},$	$L+S_1+S_2, L+S_2,$	$L^{p}+S_{1}^{1} \rightarrow S_{2}^{p},$ $L^{1p} \rightarrow S_{2}^{1p},$	$S_2^p, S_2^{1p},$
	H _{E4}	$L+S_2$, $L+S_2+CS$,	$L S_2$, $L^{ep} \rightarrow S_2^{ep(CS)} + CS^{ep(B2)}$	S_2 , $CS^{ep(CS)}$, $CS^{ep(B2)}$
	1-154	$S_2+R_4+CAS_2$	$L \xrightarrow{S_2} S_2 \xrightarrow{F+CS} L \xrightarrow{E4} S_2 \xrightarrow{E4} + CS \xrightarrow{E4} + CAS_2 \xrightarrow{E4}$	S_2^{E4} , CS^{E4} , CAS_2^{E4}
n-k	Q_{S1} ,	L+S ₁ ,	$L^1 \rightarrow S_2^{-1} CS^{-1}CAS_2^{-1}$ $L^1 \rightarrow S_1^{-1}$,	- , , , -
	Q^{r}_{p3-S} ,	$L+S_1+S_2$,	$L^p + S_1^1 \rightarrow S_2^p$,	S_2^p ,
	Q_{e3-S}^{r}	$L+S_2$,	$L^{1p} \rightarrow S_2^{1p}$.	S_2^{lp} , $S_2^{\text{ep(CS)}}$, $CS^{\text{ep(B2)}}$
	${ m H}_{ m E4}$	$L+S_2+CS$,	$L^{ep} \rightarrow S_2^{ep(CS)} + CS^{ep(B2)}$	$S_2^{\text{ep(CS)}}, CS^{\text{ep(B2)}}$
		$B_2+R_4+CAS_2$	$L^{E4} \rightarrow S_2^{E4} + CS^{E4} + CAS_2^{E4}$	S_2^{E4} , CS^{E4} , CAS_2^{E4}
m-k	Q_{S1} ,	$L+S_1$,	$L^1 \rightarrow S_1^1$,	
	i ^r m,	$L_1+L_2+S_1$,	$L_1^m \rightarrow L_2^m + S_1^m$	
	i'n,	$L+S_1$,	$L^{1}_{2} \rightarrow S_{1}^{1}$,	a n
	Q^{r}_{p3-B} ,	$L+S_1+S_2$,	$L^p+S_1^{1,1p} \rightarrow S_2^p$,	S_2^p ,
	Q ^r _{e3-B} ,	L+S ₂ , L+S ₂ +CS,	$L^{1p} \rightarrow S_2^{1p},$	S_2^{lp} , $S_2^{ep(CS)}$, $CS^{ep(B2)}$
	$ m H_{E4}$	$S_2+R_4+CAS_2$	$L^{ep} \rightarrow S_2^{ep(CS)} + CS^{ep(B2)}$	S_2^{E4} , CS^{E4} , CAS_2^{E4}
w 1 ·	, 11° , 2° T		$L^{E4} \rightarrow S_2^{E4} + CS^{E4} + CAS_2^{E4}$	

* 1 – primary crystallization $L^{1}\rightarrow I^{1}$; e – monovariant eutectic reaction $L^{e}\rightarrow I^{e}+J^{e}$; p – monovariant peritectic reaction $L^{p}+A^{p}\rightarrow R^{p}$; m – monovariant monotectic reaction $L^{m}\rightarrow L^{m}+R^{m}$; E – invariant eutectic crystallization $L^{E}\rightarrow B^{E}+C^{E}+R^{E}$; Q – invariant quasiperitectic regrouping of masses $L^{Q}+A^{Q}\rightarrow B^{Q}+R^{Q}$; 1p – post-peritectic primary crystallization $L^{1p}\rightarrow R^{1p}$; ep – post-peritectic monovariant crystallization $L^{ep}\rightarrow R^{ep}+J^{ep}$ (J=B, C).

Let's consider the diagram of mass balances for composition given in the field p_3 -1-SiO₂-k-n (figure 3). After the reaction of primary crystallization $L^1 \rightarrow S_1^{-1}$ in the phase region L+S1 the composition falls into phase region L+S₁+S₂ (degenerated into line) where the crystals S₁ is fully disappeared as the result of reactions $L^p, S_1 \rightarrow S_2^p$ and $L^U, S_1 \rightarrow S_2^U + A_3 S_2^U$. Then the composition moves into the phase region L+S₂ where the post-peritectical primary crystallization $L^{1p} \rightarrow S_2^{-1p}$ takes place with the increasing of phase part S₂. In the phase region L+S₂+CS the part of phase L is decreased and parts of phases S₂ and CS are increased: $(L^{ep} \rightarrow S_2^{ep(CS)} + CS^{ep(B2)})$. The phase L is fully disappeared as the result of reaction $L^{E4} \rightarrow S_2^{E4} + CS^{E4} + CAS_2^{E4}$ on the plane at the temperature of ternary eutectic points E₄. Below the plane the composition gets to the solid-phase region S₂+CS+CAS₂.

IOP Conf. Series: Materials Science and Engineering 47 (2013) 012047

doi:10.1088/1757-899X/47/1/012047

The concentration fields e_4 -U and U coincide with fields SiO_2 -U- e_4 μ SiO_2 -U by the microconstituents, but differ the crystallization scheme. Fields e_4 -U and U haven't the reaction of primary crystallization $L^1 \rightarrow B_1^{-1}$. The concentration fields p_3 -1 and 2 differ from fields e_3 - E_4 -1- p_3 and 2-4 by intersected surfaces. The fields E_5 -3, A_3S_2 -U μ A_3S_2 - Q_8 are identical with E_5 -U-3, U- E_5 - A_3S_2 and E_5 - Q_8 - A_3S_2 by the microconstituents and crystallization scheme correspondently.

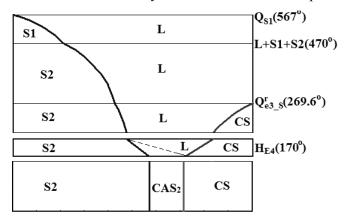


Figure 3. Diagram of material balance for the concentration field p_3 -1-SiO₂-k-n.

5. Conclusion

Computer model of PD gives the possibility to analyze the crystallization stages for any composition and to find the concentration fields both with individual set of microstructure elements and the fields at which the crystallization scheme and microconstituents of phases assemblage coincide with those in the adjoining fields. It is used as an important tool to investigate multicomponent system, to correct its constitutional diagram, to design the miscrostructures of heterogeneous material, to decipher the genotype of heterogeneous material [12]. One more reason for the microstructures variety is the competition of crystals with different dispersity, when a field of invariant reaction is divided into the fragments with the tiny eutectical crystals, with more large primary crystals and with the both type of these crystals [13].

References

- [1] Taylor H F W 1997 Cement Chemistry (London, Thomas Telford)
- [2] Lea F 1998 Lea's Chemistry of Cement and Concrete (London: P.C. Hewlett)
- [3] De Noirfontaine M N, Tusseau-Nenez S et al. 2012 J. Mater. Sci. 47 1471
- [4] Pashchenko A A, Aleksenko N V et al. 1977 *Phisical Chemistry of Silicate* ed A A Pashchenko (Kiev: Vyshcha schkola) (In Russian)
- [5] Lutsyk V I, Zelenaya A E, Savinov V V 2011 *IOP Conf. Ser.: Mater. Sci. Eng.* **18** http://iopscience.iop.org/1757-899X/18/11/112005/pdf/1757-899X 18 11 112005.pdf
- [6] Lutsyk V I, Zelenaya A E, Savinov V V 2012 Crys. Rep. 57 943
- [7] Gentile A L, Foster W R 1963 J. Amer. Cer. Soc. 46 74
- [8] Levin E M, Robbins C R and McMurdie H F 1964 *Phase Diagrams for Ceramists* (Ohio: American Ceramic Society)
- [9] Toropov N A, Bazarkovsky V P, Lapshin V V et al. 1972 *Diagrams of Silicate Systems*. vol 3. *Ternary Silicate Systems* (Leningrad: Nauka) pp 184-190 (In Russian)
- [10] Lutsyk V, Zelenaya A 2012 Proc. Int. Conf. Oxide Materials for Electronic Engineering (Lviv, Ukraine) 133
- [11] Lukas H L, Henlg E T, Petzow G 1986 Z. Metallkde. 77 360
- [12] Lutsyk V I 2012 Bulletin of Buryat Scientific Centre (SB RAS) no 1(5), 78 (In Russian)
- [13] Lutsyk V I, Nasrulin E R 2012 Crys. Rep. 57 106